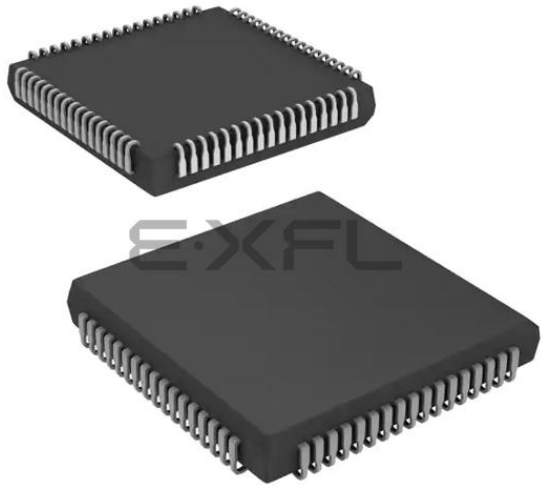

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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	57
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	68-LCC (J-Lead)
Supplier Device Package	68-PLCC (24.23x24.23)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx04-pl68i

1 Revision History

The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

1.1 Revision 15.0

The following is a summary of the changes in revision 15.0 of this document.

Table 15, page 21 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
Table 22, page 25 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
Table 23, page 25 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

1.2 Revision 14.0

The following is a summary of the changes in revision 14.0 of this document.

Added CQFP package information for A42MX16 device in Product Profile, page 1 and Ceramic Device Resources, page 4 (SAR 79522).
Added Military (M) and MIL-STD-883 Class B (B) grades for CPGA 132 Package and added Commercial (C), Military (M), and MIL-STD-883 Class B (B) grades for CQFP 172 Package in Temperature Grade Offerings, page 5 (SAR 79519)
Changed Silicon Sculptor II to Silicon Sculptor in Programming, page 12 (SAR 38754)
Added Figure 53, page 158 CQ172 package (SAR 79522).

1.3 Revision 13.0

The following is a summary of the changes in revision 13.0 of this document.

Added Figure 42, page 97 PQ144 Package for A42MX09 device (SAR 69776)
Added Figure 52, page 153 PQ132 Package for A42MX09 device (SAR 69776)

1.4 Revision 12.0

The following is a summary of the changes in revision 12.0 of this document.

Added information on power-up behavior for A42MX24 and A42MX36 devices to the Power Supply, page 13 (SAR 42096
Corrected the inadvertent mistake in the naming of the PL68 pin assignment table (SARs 48999, 49793)

1.5 Revision 11.0

The following is a summary of the changes in revision 11.0 of this document.

The FuseLock logo and accompanying text was removed from the User Security, page 12. This marking is no longer used on Microsemi devices (PCN 0915)
The Development Tool Support, page 19 was updated (SAR 38512)

1.6 Revision 10.0

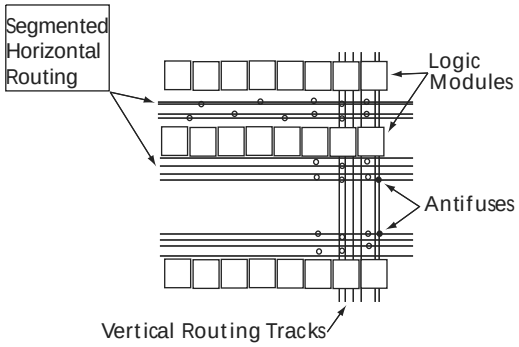
The following is a summary of the changes in revision 10.0 of this document.

Ordering Information, page 3 was updated to include lead-free package ordering codes (SAR 21968)
The User Security, page 12 was revised to clarify that although no existing security measures can give an absolute guarantee, Microsemi FPGAs implement the best security available in the industry (SAR 34673)

3.2.3.3 Antifuse Structures

An antifuse is a normally open structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Figure 7 • MX Routing Structure



3.2.4 Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 8, page 11):

Externally from the CLKA pad, using CLKBUF buffer
Externally from the CLKB pad, using CLKBUF buffer
Internally from the CLKINTA input, using CLKINT buffer
Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 9, page 11). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.

3.3.7 Low Power Mode

42MX devices have been designed with a Low Power Mode. This feature, activated with setting the special LP pin to HIGH for a period longer than 800 ns, is particularly useful for battery-operated systems where battery life is a primary concern. In this mode, the core of the device is turned off and the device consumes minimal power with low standby current. In addition, all input buffers are turned off, and all outputs and bidirectional buffers are tristated. Since the core of the device is turned off, the states of the registers are lost. The device must be re-initialized when exiting Low Power Mode. I/Os can be driven during LP mode, and clock pins should be driven HIGH or LOW and should not float to avoid drawing current. To exit LP mode, the LP pin must be pulled LOW for over 200 µs to allow for charge pumps to power up, and device initialization will begin.

3.4 Power Dissipation

The general power consumption of MX devices is made up of static and dynamic power and can be expressed with the following equation.

3.4.1 General Power Equation

$$P = [ICCstandby + ICCactive]*VCCI + IOL*VOL*N + IOH*(VCCI - VOH)*M$$

EQ 1

where:

ICCstandby is the current flowing when no inputs or outputs are changing.
ICCactive is the current flowing due to CMOS switching.
IOL, IOH are TTL sink/source currents.
VOL, VOH are TTL level output voltages.
N equals the number of outputs driving TTL loads to VOL.
M equals the number of outputs driving TTL loads to VOH.

Accurate values for N and M are difficult to determine because they depend on the family type, on design details, and on the system I/O. The power can be divided into two components: static and active.

3.4.2 Static Power Component

The static power due to standby current is typically a small component of the overall power consumption. Standby power is calculated for commercial, worst-case conditions. The static power dissipation by TTL loads depends on the number of outputs driving, and on the DC load current. For instance, a 32-bit bus sinking 4mA at 0.33V will generate 42mW with all outputs driving LOW, and 140mW with all outputs driving HIGH. The actual dissipation will average somewhere in between, as I/Os switch states with time.

3.4.3 Active Power Component

Power dissipation in CMOS devices is usually dominated by the dynamic power dissipation. Dynamic power consumption is frequency-dependent and is a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitances due to PC board traces and load device inputs. An additional component of the active power dissipation is the totem pole current in the CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

The power dissipated by a CMOS circuit can be expressed by the equation:

$$Power(\mu W) = C_{EQ} * VCCA2 * F(1)$$

EQ 2

where:

C_{EQ} = Equivalent capacitance expressed in picofarads (pF)

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • 42MX IEEE 1149.1 Bounda ry Scan Circuitry

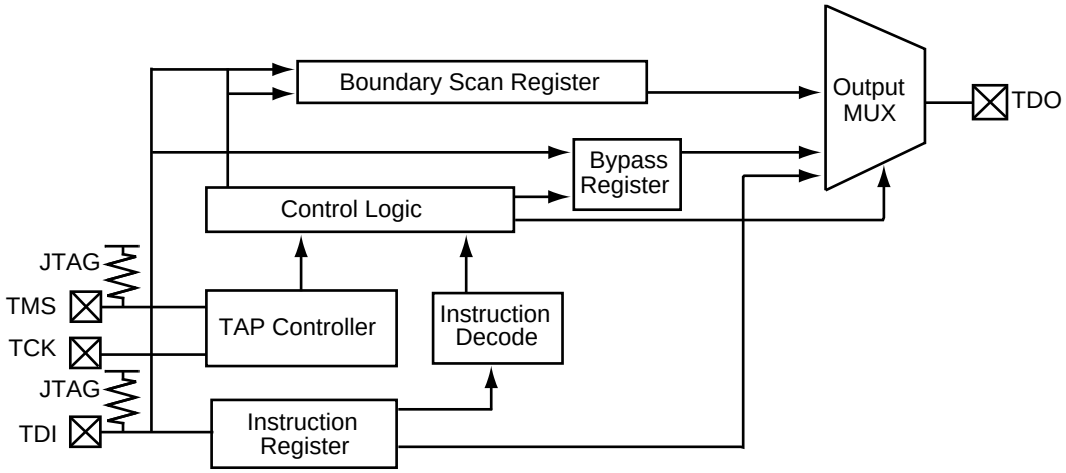


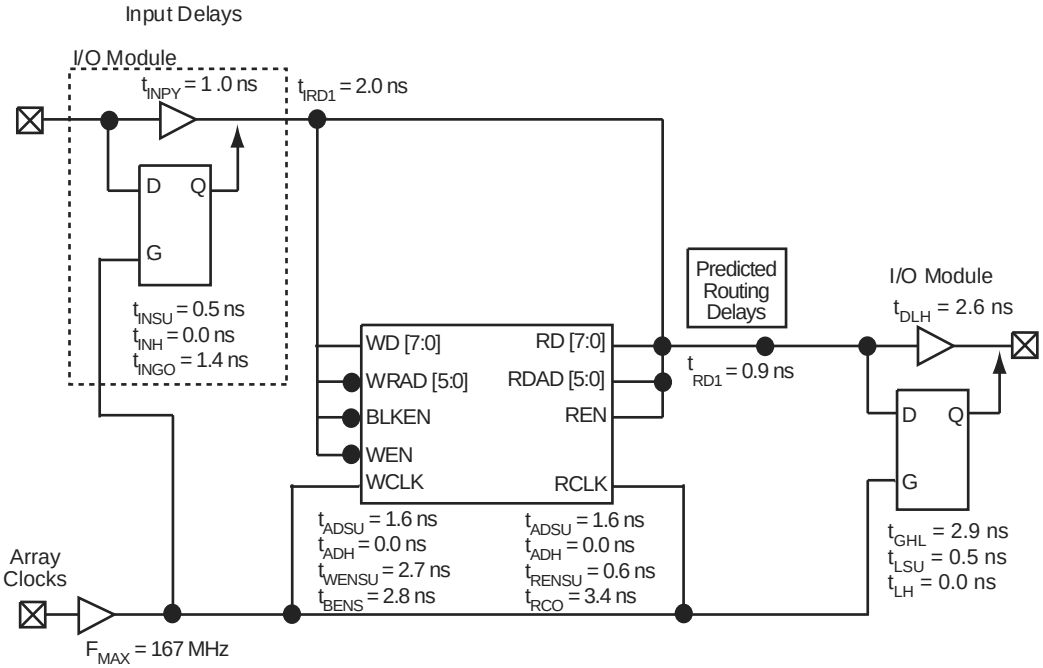
Table 9 • Test Access Port Descriptions

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 10 • Supported BST Public Instructions

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

Figure 20 • 42MX Timing Model (SRAM Functions)



Note: Values are shown for A42MX36 3 at 5. 0 V worst-case commercial conditions.

3.10.1 Parameter Measurement

The following figures show parameter measurement details.

Figure 21 • Output Buffer Delays

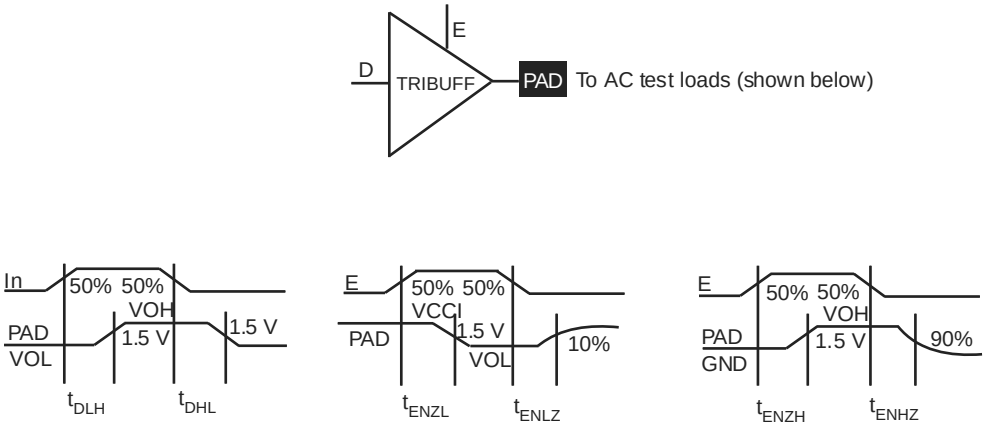
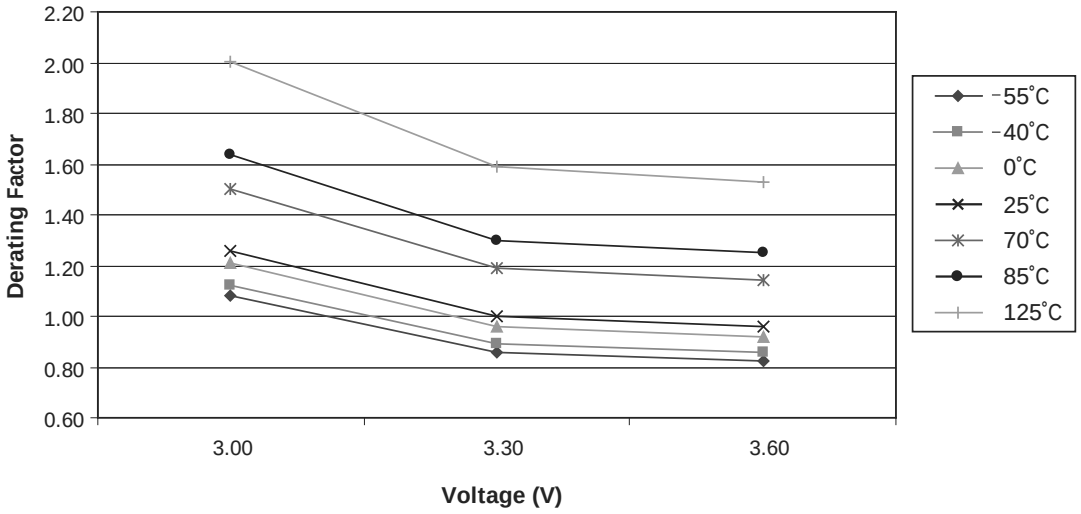


Table 31 • 40MX Temperature and Voltage Derating Factor s (Normalized to TJ = 25°C, VCC = 3.3 V)

	Temperature						
40MX Voltage	55°C	40°C	0°C	25°C	70°C	85°C	125°C
3.60	0.83	0.85	0.92	0.96	1.14	1.25	1.53

Figure 37 • 40MX Junction Temperature and Voltage Derating Curves (Normalized to T J = 25°C, VCC = 3.3 V)



Note: This derating factor applies to all routing and propagation delays

3.11.5 PCI System Timing Specification

The following tables list the critical PCI timing parameters and the corresponding timing parameters for the MX PCI-compliant devices.

3.11.6 PCI Models

Microsemi provides synthesizable VHDL and Verilog-HDL models for a PCI Target interface, a PCI Target and Target+DMA Master interface. Contact the Microsemi sales representative for more details.

Table 32 • Clock Specification for 33 MHz PCI

		PCI		A42MX24		A42MX36		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Units
t_{CYC}	CLK Cycle Time	30		4.0		4.0		ns
t_{HIGH}	CLK High Time	11		1.9		1.9		ns
t_{LOW}	CLK Low Time	11		1.9		1.9		ns

Table 33 • Timing Parameters for 33 MHz PCI

		PCI		A42MX24		A42MX36		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Units
t_{VAL}	CLK to Signal Valid Bused Signals	2	11	2.0	9.0	2.0	9.0	ns
$t_{VAL(PTP)}$	CLK to Signal Valid Point-to-Point	2 [2]	12	2.0	9.0	2.0	9.0	ns
t_{ON}	Float to Active	2		2.0	4.0	2.0	4.0	ns
t_{OFF}	Active to Float		28		8.3 [1]		8.3 [1]	ns
t_{SU}	Input Set-Up Time to CLK Bused Signals	7		1.5		1.5		ns

Table 35 • A40MX02 Timing Characteristics (Nominal 3.3 V Operation) ***(continued)***
(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		3 Speed		2 Speed		1 Speed		Std Speed		F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing [4]												
t_{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t_{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t_{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t_{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t_{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t_{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d_{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d_{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro
4. Delays based on 35 pF loading

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		3 Speed		2 Speed		1 Speed		Std Speed		F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t_{PD2}	Dual-Module Macros		2.3		3.1		3.5		4.1		5.7	ns
t_{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays [1]												
t_{RD1}	FO = 1 Routing Delay		1.2		1.6		1.8		2.1		3.0	ns
t_{RD2}	FO = 2 Routing Delay		1.9		2.2		2.5		2.9		4.1	ns
t_{RD3}	FO = 3 Routing Delay		2.4		2.8		3.2		3.7		5.2	ns
t_{RD4}	FO = 4 Routing Delay		2.9		3.4		3.9		4.5		6.3	ns
t_{RD8}	FO = 8 Routing Delay		5.0		5.8		6.6		7.8		10.9	ns
Logic Module Sequential Timing [2]												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t_{HD} [3]	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	3.1		3.5		4.0		4.7		6.6		ns

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) ***(continued)***(Worst-Case Commercial Conditions, VCCA = 4.75 V, T J = 70°C)

Parameter / Description			3 Speed		2 Speed		1 Speed		Std Speed		F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{PWL}	Minimum Pulse Width LOW	FO = 32	3.2		3.5		4.0		4.7		6.6		ns
		FO = 384	3.7		4.1		4.6		5.4		7.6		ns
t_{CKSW}	Maximum Skew	FO = 32		0.3		0.4		0.4		0.5		0.7	ns
		FO = 384		0.3		0.4		0.4		0.5		0.7	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 384	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		5.5		4.1		5.7		ns
		FO = 384	3.2		3.5		4.0		4.7		6.6		ns
t_P	Minimum Period	FO = 32	4.2		4.67		5.1		5.8		9.7		ns
		FO = 384	4.6		5.1		5.6		6.4		10.7		ns
f_{MAX}	Maximum Frequency	FO = 32		237		215		198		172		103	MHz
		FO = 384		215		195		179		156		94	MHz

Table 42 • A42MX24 Timing Characteristic s (Nominal 5.0 V Operation) ***(continued)***(Worst-Case Commercial Conditions, VCCA = 4.75 V, T J = 70°C)

Parameter / Description			3 Speed Min.	3 Speed Max.	2 Speed Min.	2 Speed Max.	1 Speed Min.	1 Speed Max.	Std Speed Min.	Std Speed Max.	F Speed Min.	F Speed Max.	Units
Input Module Predicted Routing Delays [2]													
t_{IRD1}	FO = 1 Routing Delay			1.8		2.0		2.3		2.7		3.8	ns
t_{IRD2}	FO = 2 Routing Delay			2.1		2.3		2.6		3.1		4.3	ns
t_{IRD3}	FO = 3 Routing Delay			2.3		2.5		2.9		3.4		4.8	ns
t_{IRD4}	FO = 4 Routing Delay			2.5		2.8		3.2		3.7		5.2	ns
t_{IRD8}	FO = 8 Routing Delay			3.4		3.8		4.3		5.1		7.1	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32		2.6		2.9		3.3		3.9		5.4	ns
		FO = 486		2.9		3.2		3.6		4.3		5.9	ns
t_{CKL}	Input HIGH to LOW	FO = 32		3.7		4.1		4.6		5.4		7.6	ns
		FO = 486		4.3		4.7		5.4		6.3		8.8	ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32	2.2		2.4		2.7		3.2		4.5		ns
		FO = 486	2.4		2.6		3.0		3.5		4.9		ns
t_{PWL}	Minimum Pulse Width LOW	FO = 32	2.2		2.4		2.7		3.2		4.5		ns
		FO = 486	2.4		2.6		3.0		3.5		4.9		ns
t_{CKSW}	Maximum Skew	FO = 32		0.5		0.6		0.7		0.8		1.1	ns
		FO = 486		0.5		0.6		0.7		0.8		1.1	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 486	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		3.5		4.1		5.7		ns
		FO = 486	3.3		3.7		4.2		4.9		6.9		ns
t_P	Minimum Period ($1/f_{MAX}$)	FO = 32	4.7		5.2		5.7		6.5		10.9		ns
		FO = 486	5.1		5.7		6.2		7.1		11.9		ns

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		3 Speed		2 Speed		1 Speed		Std Speed		F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions [1]												
t_{PD}	Internal Array Module Delay		1.3		1.5		1.7		2.0		2.7	ns
t_{PDD}	Internal Decode Module Delay		1.6		1.8		2.0		2.4		3.3	ns
Logic Module Predicted Routing Delays [2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.2		1.4		2.0	ns
t_{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t_{RD3}	FO =3 Routing Delay		1.6		1.8		2.0		2.4		3.4	ns
t_{RD4}	FO = 4 Routing Delay		2.0		2.2		2.5		2.9		4.1	ns
t_{RD5}	FO = 8 Routing Delay		3.3		3.7		4.2		4.9		6.9	ns
t_{RDD}	Decode-to-Output Routing Delay		0.3		0.4		0.4		0.5		0.7	ns
Logic Module Sequential Timing [3, 4]												
t_{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch Gate-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.3		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset-to-Output		1.6		1.7		2.0		2.3		3.2	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.5		6.4		9.0		ns
Synchronous SRAM Operations												
t_{RC}	Read Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{WC}	Write Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{RCKHL}	Clock HIGH/LOW Time	3.4		3.8		4.3		5.0		7.0		ns
t_{RCO}	Data Valid After Clock HIGH/LOW		3.4		3.8		4.3		5.0		7.0	ns
t_{ADSU}	Address/Data Set-Up Time	1.6		1.8		2.0		2.4		3.4		ns
Synchronous SRAM Operations (continued)												
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.6		0.7		0.8		0.9		1.3		ns
t_{RENH}	Read Enable Hold	3.4		3.8		4.3		5.0		7.0		ns
t_{WENSU}	Write Enable Set-Up	2.7		3.0		3.4		4.0		5.6		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	2.8		3.1		3.5		4.1		5.7		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/OTest Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/OTest Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/OTest Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10kΩ pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/OWide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Table 47 • PL44

PL44		
Pin Number	A40MX02 Function	A40MX04 Function
21	GND	GND
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	VCC	VCC
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	CLK, I/O	CLK, I/O
34	MODE	MODE
35	VCC	VCC
36	SDI, I/O	SDI, I/O
37	DCLK, I/O	DCLK, I/O
38	PRA, I/O	PRA, I/O
39	PRB, I/O	PRB, I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	GND	GND
44	I/O	I/O

Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
47	I/O	I/O	I/O	WD, I/O
48	I/O	I/O	I/O	I/O
49	I/O	GND	GND	GND
50	I/O	I/O	I/O	WD, I/O
51	I/O	I/O	I/O	WD, I/O
52	I/O	SDO, I/O	SDO, I/O	SDO, TDO, I/O
53	I/O	I/O	I/O	I/O
54	I/O	I/O	I/O	I/O
55	I/O	I/O	I/O	I/O
56	I/O	I/O	I/O	I/O
57	I/O	I/O	I/O	I/O
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	GND	I/O	I/O	I/O
61	GND	I/O	I/O	I/O
62	I/O	I/O	I/O	TCK, I/O
63	I/O	LP	LP	LP
64	CLK, I/O	VCCA	VCCA	VCCA
65	I/O	VCCI	VCCI	VCCI
66	MODE	I/O	I/O	I/O
67	VCC	I/O	I/O	I/O
68	VCC	I/O	I/O	I/O
69	I/O	I/O	I/O	I/O
70	I/O	GND	GND	GND
71	I/O	I/O	I/O	I/O
72	SDI, I/O	I/O	I/O	I/O
73	DCLK, I/O	I/O	I/O	I/O
74	PRA, I/O	I/O	I/O	I/O
75	PRB, I/O	I/O	I/O	I/O
76	I/O	SDI, I/O	SDI, I/O	SDI, I/O
77	I/O	I/O	I/O	I/O
78	I/O	I/O	I/O	WD, I/O
79	I/O	I/O	I/O	WD, I/O
80	I/O	I/O	I/O	WD, I/O
81	I/O	PRA, I/O	PRA, I/O	PRA, I/O
82	GND	I/O	I/O	I/O
83	I/O	CLKA, I/O	CLKA, I/O	CLKA, I/O

Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
80	GNDI
81	NC
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	I/O
88	VKS
89	VPP
90	VCC
91	VCCI
92	NC
93	VSV
94	I/O
95	I/O
96	I/O
97	I/O
98	I/O
99	I/O
100	GND
101	GNDI
102	NC
103	I/O
104	I/O
105	I/O
106	I/O
107	I/O
108	I/O
109	I/O
110	SDI
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	GNDQ

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
95	NC	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	VCCI	VCCI	VCCI
99	I/O	I/O	I/O
100	I/O	WD, I/O	WD, I/O
101	I/O	WD, I/O	WD, I/O
102	I/O	I/O	I/O
103	SDO, I/O	SDO, TDO, I/O	SDO, TDO, I/O
104	I/O	I/O	I/O
105	GND	GND	GND
106	NC	VCCA	VCCA
107	I/O	I/O	I/O
108	I/O	I/O	I/O
109	I/O	I/O	I/O
110	I/O	I/O	I/O
111	I/O	I/O	I/O
112	NC	I/O	I/O
113	NC	I/O	I/O
114	NC	I/O	I/O
115	NC	I/O	I/O
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	I/O	I/O	I/O
126	GND	GND	GND
127	I/O	I/O	I/O
128	I/O	TCK, I/O	TCK, I/O
129	LP	LP	LP
130	VCCA	VCCA	VCCA
131	GND	GND	GND

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
169	I/O	WD, I/O	WD, I/O
170	I/O	I/O	I/O
171	NC	I/O	QCLKD, I/O
172	I/O	I/O	I/O
173	I/O	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	I/O	WD, I/O	WD, I/O
177	I/O	WD, I/O	WD, I/O
178	PRA, I/O	PRA, I/O	PRA, I/O
179	I/O	I/O	I/O
180	CLKA, I/O	CLKA, I/O	CLKA, I/O
181	NC	I/O	I/O
182	NC	VCCI	VCCI
183	VCCA	VCCA	VCCA
184	GND	GND	GND
185	I/O	I/O	I/O
186	CLKB, I/O	CLKB, I/O	CLKB, I/O
187	I/O	I/O	I/O
188	PRB, I/O	PRB, I/O	PRB, I/O
189	I/O	I/O	I/O
190	I/O	WD, I/O	WD, I/O
191	I/O	WD, I/O	WD, I/O
192	I/O	I/O	I/O
193	NC	I/O	I/O
194	NC	WD, I/O	WD, I/O
195	NC	WD, I/O	WD, I/O
196	I/O	I/O	QCLKC, I/O
197	NC	I/O	I/O
198	I/O	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	NC	I/O	I/O
202	VCCI	VCCI	VCCI
203	I/O	WD, I/O	WD, I/O
204	I/O	WD, I/O	WD, I/O
205	I/O	I/O	I/O

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	I/O	I/O
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	VCCA	VCCA
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	GND	GND
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	I/O	I/O
50	SDO, I/O	SDO, I/O
51	I/O	I/O
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	GND	GND
56	I/O	I/O

Figure 50 • CQ256

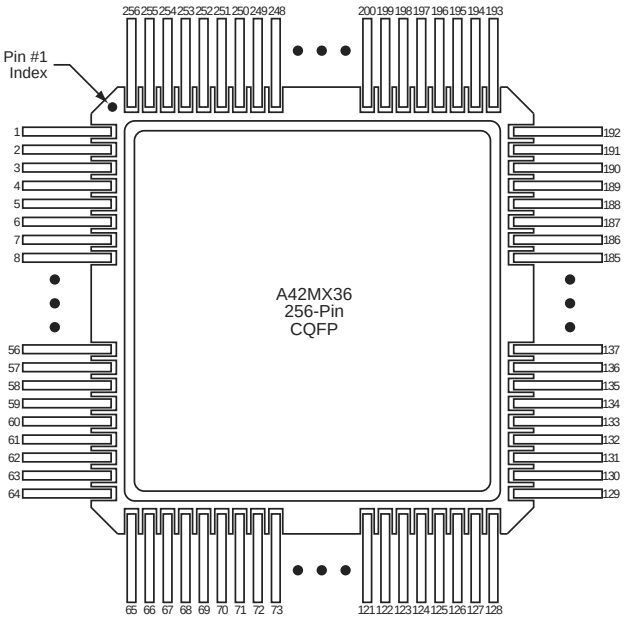


Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
1	NC
2	GND
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	GND
11	I/O
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
207	I/O
208	I/O
209	QCLKC, I/O
210	I/O
211	WD, I/O
212	WD, I/O
213	I/O
214	I/O
215	WD, I/O
216	WD, I/O
217	I/O
218	PRB, I/O
219	I/O
220	CLKB, I/O
221	I/O
222	GND
223	GND
224	VCCA
225	VCCI
226	I/O
227	CLKA, I/O
228	I/O
229	PRA, I/O
230	I/O
231	I/O
232	WD, I/O
233	WD, I/O
234	I/O
235	I/O
236	I/O
237	I/O
238	I/O
239	I/O
240	QCLKD, I/O
241	I/O
242	WD, I/O
243	GND

Table 62 • CQ172

21	I/O
22	GND
23	VCCI
24	VSV
25	I/O
26	I/O
27	VCC
28	I/O
29	I/O
30	I/O
31	I/O
32	GND
33	I/O
34	I/O
35	I/O
36	I/O
37	GND
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	BININ
45	BINOUT
46	I/O
47	I/O
48	I/O
49	I/O
50	VCCI
51	I/O
52	I/O
53	I/O
54	I/O
55	GND
56	I/O
57	I/O
58	I/O
59	I/O